TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSVI)

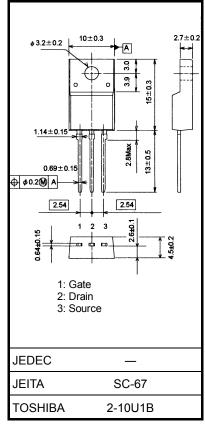
# 2SK3567

#### Switching Regulator Applications

- Low drain-source ON resistance:  $RDS(ON) = 1.7 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 2.5S$  (typ.)
- Low leakage current:  $I_{DSS} = 100 \ \mu A (V_{DS} = 600 \text{ V})$
- Enhancement mode:  $V_{th} = 2.0 \sim 4.0 \text{ V} (V_{DS} = 10 \text{ V}, \text{ID} = 1 \text{ mA})$

#### Unit Characteristics Symbol Rating Drain-source voltage 600 ٧ VDSS 600 Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ ) V VDGR V Gate-source voltage ±30 VGSS DC (Note 1) $I_D$ 3.5 Drain current Α Pulse (t = 1 ms) 14 IDP (Note 1) Drain power dissipation (Tc = 25°C) 35 w $\mathsf{P}_\mathsf{D}$ Single pulse avalanche energy E<sub>AS</sub> 201 mJ (Note 2) Avalanche current 35 А $I_{AR}$ Repetitive avalanche energy (Note 3) $\mathsf{E}_{\mathsf{AR}}$ 3.5 mJ °C Channel temperature T<sub>ch</sub> 150 °C Storage temperature range Tstg -55~150





Weight : 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

#### **Thermal Characteristics**

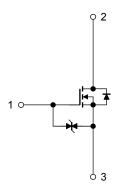
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.57	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = 90 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}(\text{initial}), \text{ L} = 28.8 \text{ mH}, \text{ I}_{AR} = 3.5 \text{ A}, \text{ R}_{G} = 25 \Omega$ 

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.



Unit: mm

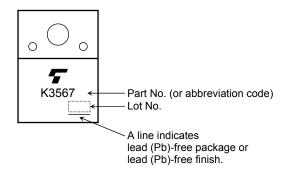
**Electrical Characteristics (Ta = 25°C)** 

Char	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	Gate leakage current $I_{GSS}$ $V_{GS} = \pm 25$ V, $V_{DS} = 0$ V		$V_{GS}=\pm 25~V,~V_{DS}=0~V$	_		±10	μA
Gate-source brea	akdown voltage	V (BR) GSS	$I_G=\pm 10~\mu A,~V_{DS}=0~V$	±30			V
Drain cut-off curr	rent	I <sub>DSS</sub>	$V_{DS} = 600 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_		100	μA
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	600			V
Gate threshold v	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	2.0		4.0	V
Drain-source ON	resistance	R <sub>DS (ON)</sub>	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 1.8 \text{ A}$		1.7	2.2	Ω
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1.8 \text{ A}$	0.7	2.5		S
Input capacitance	e	C <sub>iss</sub>		_	550		
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS}$ = 25 V, $V_{GS}$ = 0 V, f = 1 MHz		6		pF
Output capacitance		C <sub>oss</sub>			60		
Switching time	Rise time	tr	$V_{GS}$ $0 V$ $V_{DD} \simeq 200 V$ $I_{D} = 1.8 \text{ A } V_{OUT}$ $R_{L} =$ $111 \Omega$		12		• ns
	Turn-on time	t <sub>on</sub>		_	45	_	
	Fall time	t <sub>f</sub>		_	13	_	
	Turn-off time	t <sub>off</sub>	Duty $\leq$ 1%, t <sub>w</sub> = 10 $\mu$ s		80	_	
Total gate charge Qg		Qg		_	16		
Gate-source charge		Q <sub>gs</sub>	$V_{DD}\simeq 400~V,~V_{GS}=10~V,~I_{D}=3.5~A$	_	10		nC
Gate-drain charge		Q <sub>gd</sub>			6		

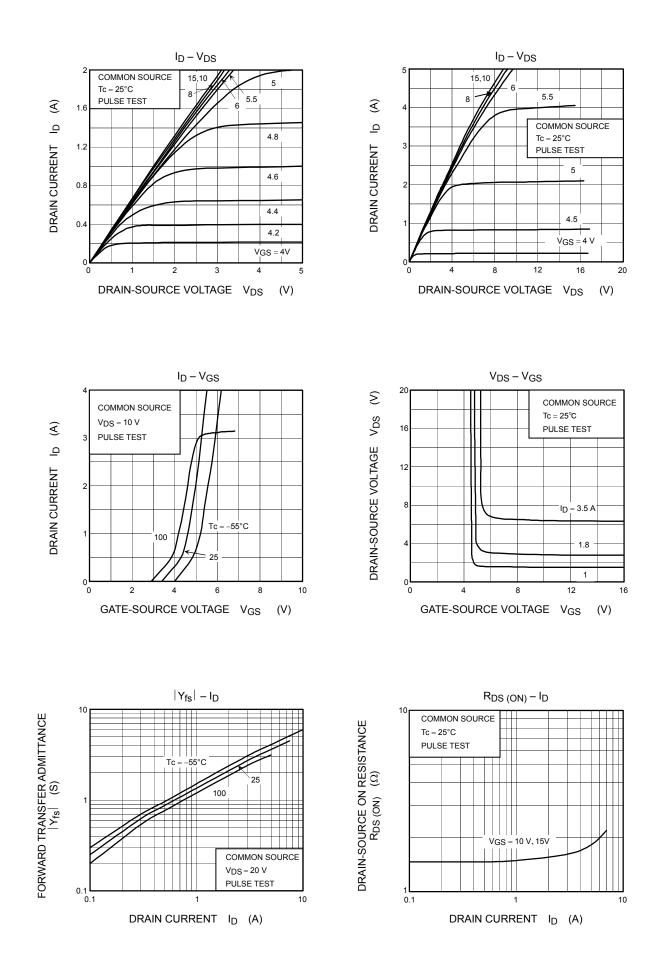
### Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	—	_	_	3.5	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	—	_		14	А
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = 3.5 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 3.5 \text{ A}, V_{GS} = 0 \text{ V},$	_	1400	_	ns
Reverse recovery charge	Qrr	dl <sub>DR</sub> /dt = 100 A/μs		9.0	_	μC

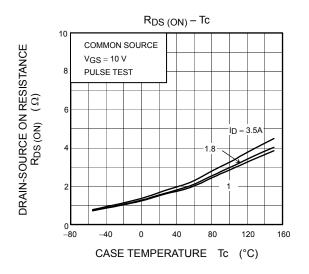
### Marking

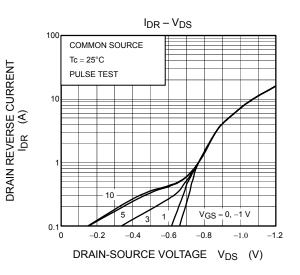


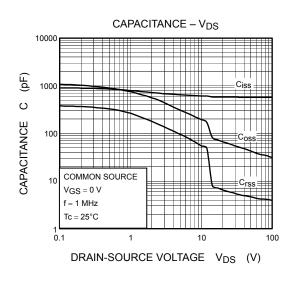
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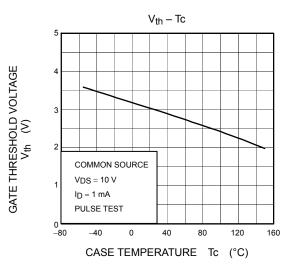


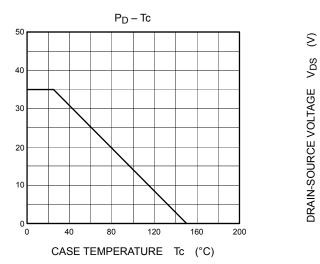
## **TOSHIBA**





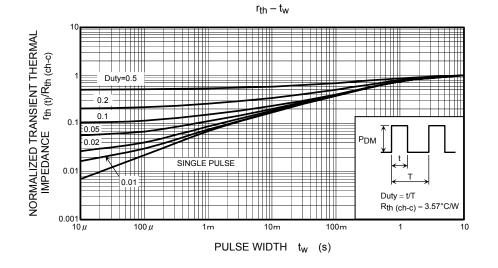


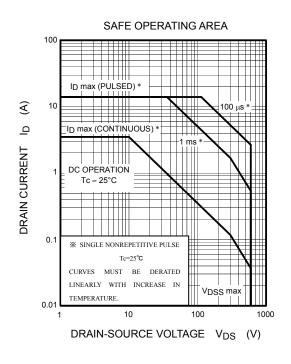


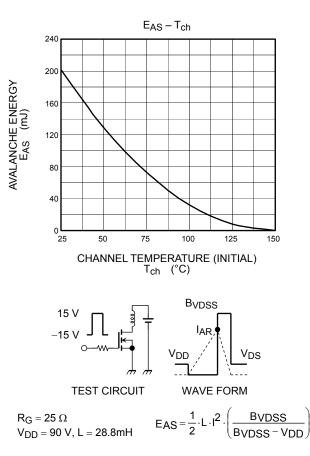


DRAIN POWER DISSIPATION PD (W)

DYNAMIC INPUT / OUTPUT CHARACTERISTICS 500 20 S V<sub>GS</sub> 400 16 VDS VDD = 100 V GATE-SOURCE VOLTAGE 300 12 200 200 400 COMMON SOURCE VGS  $I_D = 3.5 \, A$ 100  $Tc = 25^{\circ}C$ PULSE TEST 0 0 5 10 15 20 25 TOTAL GATE CHARGE Qg (nC)







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